

L Number	Hits	Search Text	DB	Time stamp
16	0	385/37.ccls. and (echelle with ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:09
17	16	385/37.ccls. and (echelle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:09
18	0	(echelle near3 grating near5 ellipt\$5) with facet	USPAT; EPO; JPO; DERWENT	2003/06/18 18:10
19	0	(echelle near3 grating near5 ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:10
20	0	(echelle near grating with ellipt\$5)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
21	0	(echelle near grating) with ellipt\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
22	184	(echelle near grating)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:11
23	23	(echelle near grating).ti.	USPAT; EPO; JPO; DERWENT	2003/06/18 18:12
24	0	(echelle near grating) with definition	USPAT; EPO; JPO; DERWENT	2003/06/18 18:12
25	0	(echelle near grating) with defin\$1	USPAT; EPO; JPO; DERWENT	2003/06/18 18:13
26	6	(echelle near3 grating) with defin\$3	USPAT; EPO; JPO; DERWENT	2003/06/18 18:13
27	6	(echelle near3 grating) with defin\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:14
28	1	(echelle near3 grating) with astigmat\$4	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
29	15	(echelle near3 grating) with fac\$5	USPAT; EPO; JPO; DERWENT	2003/06/18 18:42
30	2	("4205229" "5018856").PN.	USPAT	2003/06/18 18:22
31	3	6078048.URPN.	USPAT	2003/06/18 18:23
32	2	6067197.URPN.	USPAT	2003/06/18 18:23
33	10	(echelle near3 grating) and (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:54
34	0	(echelle near3 grating) near7 (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:55
35	0	(echelle near3 grating) with (rowland near circle)	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
36	1	("20020131708").PN.	USPAT; EPO; JPO; DERWENT	2003/06/18 18:57
37	37	(echelle near grating) with order	USPAT; EPO; JPO; DERWENT	2003/06/18 18:58

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

Membership Publications/Services Standards Conferences Careers/Jobs

IEEE Xplore[®]
RELEASE 1.4Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer](#) [Quick Links](#) [» Search](#)
[Review](#)Welcome to IEEE Xplore[®]

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 Print FormatYour search matched **8** of **943962** documents.

A maximum of **8** results are displayed, **25** to a page, sorted by **Relevance** in **descending** order.
You may refine your search by editing the current search expression or entering a new one in the text box.
Then click **Search Again**.

(echelle grating)

[Search Again](#)**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Using a retro-reflecting echelle grating to improve WDM demux efficiency**

Erickson, L.; Lamontagne, B.; He, J.J.; Delage, A.; Davies, M.; Koteles, E.;
Vertical-Cavity Lasers, Technologies for a Global Information Infrastructure, W
Components Technology, Advanced Semiconductor Lasers ..., Gallium Nitride
Materials, Processing, ..., 1997 Digest of the IEEE/LEOS Summer Topical Meeti
11-15 Aug. 1997
Page(s): 82 -83

[\[Abstract\]](#) [\[PDF Full-Text \(140 KB\)\]](#) **IEEE CNF****2 Planar waveguide echelle gratings: an embeddable diffractive element for photonic integrated circuits**

*Janz, S.; Pearson, M.; Lamontagne, B.; Erickson, L.; Delage, A.; Cheben, P.; X
D.-X.; Gao, M.; Balakrishnan, A.; Miller, J.; Charbonneau, S.;*
Optical Fiber Communication Conference and Exhibit, 2002. OFC 2002 , 17-22
2002
Page(s): 69 -70

[\[Abstract\]](#) [\[PDF Full-Text \(297 KB\)\]](#) **IEEE CNF****3 Wideband tuning of a XeCl laser-pumped dye-doped sol-gel silica laser**

Lam, K.S.; Lo, D.; Wong, K.H.;
Photonics Technology Letters, IEEE , Volume: 7 Issue: 3 , March 1995
Page(s): 306 -308

[\[Abstract\]](#) [\[PDF Full-Text \(212 KB\)\]](#) **IEEE JNL****4 Monolithically integrated wavelength demultiplexer based on a waveguide**

R wland circle grating in InGaAsP/InP

Jian-Jun He; Lamontagne, B.; Delage, A.; Erickson, L.; Davies, M.; Koteles, E.
Lightwave Technology, Journal of , Volume: 16 Issue: 4 , April 1998
Page(s): 631 -638

[\[Abstract\]](#) [\[PDF Full-Text \(168 KB\)\]](#) **IEEE JNL**

5 Phase-dithered waveguide grating with flat passband and sharp tran

Jian-Jun He;
Selected Topics in Quantum Electronics, IEEE Journal on , Volume: 8 Issue: 6 ,
Nov.-Dec. 2002
Page(s): 1186 -1193

[\[Abstract\]](#) [\[PDF Full-Text \(679 KB\)\]](#) **IEEE JNL**

6 Echelle Grating Spectrometer Integrated With Curved Output Waveg

Fallahi, M.; McGreer, K.A.; Delage, A.; Normandin, R.; Templeton, I.M.; Barbe
Chatenoud, F.;
Broadband Analog and Digital Optoelectronics, Optical Multiple Access Network
Integrated Optoelectronics, Smart Pixels, LEOS 1992 Summer Topical Meeting
on , 29 July-12 Aug. 1992
Page(s): B9 -B10

[\[Abstract\]](#) [\[PDF Full-Text \(76 KB\)\]](#) **IEEE CNF**

**7 Demonstration of grating demultiplexer in GaAs/AlGaAs suitable f r
integration**

Fallahi, M.; McGreer, K.A.; Delage, A.; Normandin, R.; Templeton, I.M.; Barbe
Chatenoud, F.; Champion, G.;
Electronics Letters , Volume: 28 Issue: 24 , 19 Nov. 1992
Page(s): 2217 -2218

[\[Abstract\]](#) [\[PDF Full-Text \(192 KB\)\]](#) **IEE JNL**

**8 Characteristics of organic dye lasers as tunable frequency sources f
nanosecond absorption spectroscopy**

Bradley, D.; Durrant, A.; Gale, G.; Moore, M.; Smith, P.;
Quantum Electronics, IEEE Journal of , Volume: 4 Issue: 11 , Nov 1968
Page(s): 707 -711

[\[Abstract\]](#) [\[PDF Full-Text \(760 KB\)\]](#) **IEEE JNL**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved .